## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10540311	AUGUSTUS ET AL.
Examiner	Art Unit
Young J Kim	1637

SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES				
Search Notes	Date	Examiner		
re-reviewed the STIC-assisted search of SEQ ID Numbers 1 and 7	5/29/2009	/YJK/		
STIC- search reviewed	1/8/2010	/YJK/		
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosed for text-search strategy	1/8/2010	/YJK/		
updated	8/2/2010	/YJK/		
updated patent database search (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosef for text-search strategy	11/22/2010	/YJK/		
updated	2/15/2011	/YJK/		
updated	6/16/2011	/YJK/		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
	Interference search history - see enclosed	1/8/2010	/YJK/	
	updated interference search - see enclosed for strategy	11/22/2010	/YJK/	

	/Young J Kim/ Primary Examiner.Art Unit 1637
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